Abstract Example

Please Note: this is just an example; it is not a requirement to follow this outline

1. **Title of Paper**: How to reduce the overall cost of testing Power Management ICs (PMICs) on the V93000

2. **Motivation/Problem Statement**: Why do we care about the topic? What is the goal of this paper?
   
   **Goal**: Minimizing the production test time for any device is a key financial metric to the product release. This paper will show how to test 16 PMIC devices in 5 seconds in a production test flow.

3. **Methods/Procedure/Approach**: What topics will your paper cover? How do we achieve this?
   
   a. Test list by IP block
   
   b. Key methodologies that allow us to achieve the desired goals
      
      i. Smart Calc – theory and code examples
      
      ii. Testing IPs in parallel for each site – theory and code examples
      
      iii. Using DC Scale anchor points to make pattern-based measurements – theory
      
      iv. Using Smart RDI as a user-friendly way for pattern-based measurements – theory and code examples
   
   c. DUT board considerations
      
      i. Layout of the multi-site that helps to improve accuracy and reduce wait times
      
      ii. Other special things done – what and why

4. **Results/Findings/Product**: As a result of completing the above procedure, what are the results and what did you learn/invent/create?
   
   **Results**:
   
   a. Achieved this test time or possibly a reduction in percentage or test time over previous methods
      
      i. Breakdown of test time if possible
   
   b. What other benefits were achieved with the lower test time?
      
      i. Better utilization of tester HW

5. **Conclusion/Implications**: What are the larger implications of your findings, especially for the problem/gap identified in step 2?
   
   **Conclusion**:
   
   a. Very high-level summary of results
      
      i. Went from test time x to test time y
      
      ii. What are the biggest contributors to the test time reductions?
   
   b. I discovered these things throughout the development process
      
      i. System and software learnings
      
      ii. Device learnings
   
   c. Next time I am going to do these things differently
      
      i. Reorganize the test flow
      
      ii. Use this new feature
      
      iii. Try this different test methodology where I expect these benefits